	Type	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	72	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1) with semiconductor$1 and (isolat$3 or tri-stat$3) with memory with (power$3 or electric$4) with (shut-down or shutdown or shut adj down or isolat$3 or disconnect$3) and terminal$1 and memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 10:34	
2	BRS	73	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3) with memory with (power$3 or electric$4) with (shut-down or shutdown or shut adj down or isolat$3 or disconnect$3) and terminal$1 and memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 10:40	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
3	BRS	2	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3) with driv$3 with memory with (power$3 or electric$4) with (shut-down or shutdown or shut adj down or isolat$3 or disconnect$3) and terminal$1 and memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 10:35	
4	BRS	8	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3) with memory with (power$3 or electric$4) with (shut-down or shutdown or shut adj down or isolat$3 or disconnect$3) with terminal$1 and memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 10:39	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
5	BRS	2	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3) with memory with (power$3 or electric$4) with (shut-down or shutdown or shut adj down or isolat$3 or disconnect$3) with terminal$1 and program$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 10:39	
6	BRS	6	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3) with memory with (power$3 or electric$4) with (shut-down or shutdown or shut adj down or isolat$3 or disconnect$3) with terminal$1 and (routine$1 or program$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 10:39	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
7	BRS	6	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3) with connect$ with (power$3 or electric$4) and terminal$1 with shar$3 and memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 10:51	
8	BRS	1	select$3 with test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3 or disconnect$3) with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with connect$ with (power$3 or electric$4) and terminal$1 and memory and (power$3 or electric$4) with (down or shutdown or disconnect$3) and (test$3 or operat$3) with mode$1 and shar$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 14:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
9	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and tri-stat$3 with driver$1 with connection$1 with shar$3 with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 11:44	
10	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disconnect$3 or isolat43 or tri-stat$3) with driver$1 with connection$1 with shar$3 with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 11:45	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
11	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disconnect$3 or isolat$3 or tri-stat$3) with (input/output or I/O) with connection$1 with shar$3 with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 11:45	
12	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disconnect$3 or isolat$3 or tri-stat$3) with (driv$3 or input/output or I/O) with connection$1 with shar$3 with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 11:46	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
13	BRS	9	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disconnect$3 or isolat$3 or tri-stat$3) with (driv$3 or input/output or I/O) with connection$1 with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 11:46	
14	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3 or disconnect$3) with driv$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with terminal41	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 12:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
15	BRS	16	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3 or disconnect$3) with driv$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 12:18	
16	BRS	18	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with packag$3 and semiconductor$1 and (isolat$3 or tri-stat$3 or disconnect$3) with memory with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 14:06	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
17	BRS	89	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3 or disconnect$3) with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with connect$4 with (power$3 or electric$4) and terminal$1 and memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 14:30	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
18	BRS	44	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3 or disconnect$3) with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with connect$4 with (power$3 or electric$4) and terminal$1 and memory and (power$3 or electric$4) with (down or shutdown or disconnect$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 14:30	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
19	BRS	19	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3 or disconnect$3) with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with connect$4 with (power$3 or electric$4) and terminal$1 and memory and (power$3 or electric$4) with (down or shutdown or disconnect$3) and (test$3 or operat$3) with mode$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 14:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
20	BRS	9	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (isolat$3 or tri-stat$3 or disconnect$3) with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with connect$4 with (power$3 or electric$4) and terminal$1 and memory and (power$3 or electric$4) with (down or shutdown or disconnect$3) and (test$3 or operat$3) with mode$1 and shar$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:41	
21	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and tri-stat$3 with shar$3 with terminal$1 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:02	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
22	BRS	7	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and tri-stat$3 and shar$3 with terminal$1 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:21	
23	IS&R	2	("6732304").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:08	
24	BRS	2	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disable$1 or tri-stat$3) with normal with operat$3 and (power$3 or electric$4) with (down or shutdown or disconnect$3 or isolat$3) and shar$3 with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:18	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
25	BRS	30	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disable$1 or tri-stat$3) with normal with operat$3 and (power$3 or electric$4) with (down or shutdown or disconnect$3 or isolat$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:22	
26	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disable$1 or tri-stat$3) with normal with operat$3 and (power$3 or electric$4) with (down or shutdown or disconnect$3 or isolat$3) and multi-chip	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:23	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
27	BRS	19	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disable$1 or tri-stat$3) with normal with operat$3 and (power$3 or electric$4) with (down or shutdown or disconnect$3 or isolat$3) and (chips or multi-chip)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:24	
28	BRS	8	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disable$1 or tri-stat$3) with normal with operat$3 and (power$3 or electric$4) with (down or shutdown or disconnect$3 or isolat$3) and (chips or multi-chip) and (software or program$4 or routine$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:27	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
29	BRS	8	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disable$1 or tri-stat$3) with normal with operat$3 and (power$3 or electric$4) with (down or shutdown or disconnect$3 or isolat$3) and (chips or multichip$1 or multi-chip$1) and (software or program$4 or routine$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:27	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
30	BRS	6	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disable$1 or tri-stat$3) with normal with operat$3 and (power$3 or electric$4) with (down or shutdown or disconnect$3 or isolat$3) and (chips or multichip$1 or multi-chip$1) and (software or program$4 or routine$1) and terminal$1 and package$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:30	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
31	BRS	6	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (disable$1 or tri-stat$3) with normal with operat$3 and power$3 with (down or shutdown or disconnect$3 or isolat$3) and (chips or multichip$1 or multi-chip$1) and terminal$1 and package$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:30	
32	BRS	151	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (voltage$1 or current$1 or power$3 or electric$4) with (down or shutdown or disconnect$3 or inactivat$3) and (multi-chip$1 or multichip$1 or shar$3) with packag$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:44	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
33	BRS	33	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (voltage$1 or current$1 or power$3 or electric$4) with (down or shutdown or disconnect$3 or inactivat$3) and (multi-chip$1 or multichip$1 or shar$3) with packag$3 with terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:49	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
34	BRS	10	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 and (voltage$1 or current$1 or power$3 or electric$4) with (down or shutdown or disconnect$3 or inactivat$3) and (multi-chip$1 or multichip$1 or shar$3) with packag$3 with terminal$1 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/07 15:51	
35	BRS	147	perform$4 with test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 with (program$4 or routine$1 or code$1 or software$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:16	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
36	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 with (program$4 or routine$1 or code$1 or software$1) and tri-stat$3 and shar$3 with terminal$1 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:17	
37	BRS	7	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 with (program$4 or routine$1 or code$1 or software$1) and tri-stat$3 and terminal$1 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:32	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
38	BRS	3	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with semiconductor$1 with (program$4 or routine$1 or code$1 or software$1) and tri-stat$3 and shar$3 and terminal$1 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:21	
39	BRS	38	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) and tri-stat$3 and terminal$1 with packag$3 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:33	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
40	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) with tri-stat$3 and terminal$1 with packag$3 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:33	
41	BRS	2	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) with tri-stat$3 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:34	
42	BRS	13	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) same tri-stat$3 and logic with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:35	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
43	BRS	10	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) same tri-stat$3 and logic with memory and terminal$1 and packag$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:35	
44	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) same tri-stat$3 and logic with memory and terminal$1 and packag$3 and (multi-chip$1 or multi adj chip$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:40	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
45	BRS	10	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) same tri-stat$3 and logic with memory and terminal$1 and packag$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:40	
46	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) same tri-stat$3 and logic with memory and terminal$1 and (multi-chip$1 or multi adj chip$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:40	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
47	BRS	0	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) same tri-stat$3 and logic with memory and (multi-chip$1 or multi adj chip$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:41	
48	BRS	14	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) and tri-stat$3 and logic with memory and (multi-chip$1 or multi adj chip$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:42	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
49	BRS	13	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (program$4 or routine$1 or code$1 or software$1) and tri-stat$3 and terminal$1 with shar$3 and (packag$3 or multi-chip$1 or multi adj chip$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:44	
50	BRS	6	test$3 with (IC$1 or integrated adj circuit$1 or wafer$1 or chip$1 or die$1) with (packag$3 or multi-chip$1 or multi adj chip$1) with (program$4 or routine$1 or code$1 or software$1) and tri-stat$3 and terminal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:48	
51	BRS	1	test$3 with (multi-chip$1 or multi adj chip$1) with (program$4 or routine$1 or code$1 or software$1) and tri-stat$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:39	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
52	BRS	1	test$3 with (multi-chip$1 or multi adj chip$1) with (program$4 or routine$1 or code$1 or software$1) and (tristat$3 or tri-stat$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:55	
53	BRS	1	test$3 with (multi-chip$1 or multi adj chip$1) with (program$4 or routine$1 or code$1 or software$1) and (voltage$1 or current$1 or electric$4 or power$3) with (down or shutdown or shut-down)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 10:57	
54	BRS	9	test$3 with (multi-chip$1 or multi adj chip$1) with (program$4 or routine$1 or code$1 or software$1) and (voltage$1 or current$1 or electric$4 or power$3) with (isolat$3 or disconnect$3 or down or shutdown or shut-down)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 11:05	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
55	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) with (program$4 or routine$1 or code$1 or software$1) same (voltage$1 or current$1 or electric$4 or power$3) with (isolat$3 or disconnect$3 or down or shutdown or shut-down)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:23	
56	IS&R	2	("5544174").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 11:05	
57	BRS	2	"20030235929"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:21	
58	BRS	17	test$3 with (multi-chip$1 or multi adj chip$1) same (voltage$1 or current$1 or electric$4 or power$3) with (inactivat$3 or isolat$3 or disconnect$3 or down or shutdown or shut-down)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:32	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
59	BRS	10	test$3 with (multi-chip$1 or multi adj chip$1) same (voltage$1 or current$1 or electric or power$3) with (inactivat$3 or isolat$3 or disconnect$3 or down or shutdown or shut-down)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:32	
60	BRS	5	test$3 with (multi-chip$1 or multi adj chip$1) with (program$4 or routine$1 or code$1 or software$1) and (normal or operat$5) with test$3 with mode$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:41	
61	BRS	122	test$3 with (multi-chip$1 or multi adj chip$1) and (normal or operat$5) with test$3 with mode$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:41	
62	BRS	19	test$3 with (multi-chip$1 or multi adj chip$1) and (transit$6 or transfer$3) with (normal or operat$5) with test$3 with mode$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:40	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
63	BRS	1	test$3 with (multi-chip$1 or multi adj chip$1) and (transit$6 or transfer$3) with (normal or operat$5) with test$3 with mode$1 and tri-stat$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:44	
64	BRS	5863	324/755,756,758,760,765.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:51	
65	BRS	1138	700/121.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:52	
66	BRS	2294	711/2,129,170,171.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 12:52	
67	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and measur$6 with standby with current$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:09	
68	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and measur$6 with (stand adj by) with current$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:09	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
69	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and measur$6 with stand-by with current$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:09	
70	BRS	75	test$3 with (multi-chip$1 or multi adj chip$1) and measur$6 with current$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:12	
71	BRS	10	test$3 with (multi-chip$1 or multi adj chip$1) and standby with current$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:30	
72	BRS	13	test$3 with (multi-chip$1 or multi adj chip$1) and (pre-charg$3 or precharg$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:33	
73	BRS	4	test$3 with (multi-chip$1 or multi adj chip$1) and (pre-charg$3 or precharg$3) with chip$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:37	
74	BRS	2	test$3 with (multi-chip$1 or multi adj chip$1) and (transit$6 or transfer$3) with (normal or operat$5) with test$3 with mode$1 and (pre-charg$3 or precharg$3) with chip$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:42	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
75	BRS	2	test$3 with (multi-chip$1 or multi adj chip$1) and (transit$6 or transfer$3) with (normal or operat$5) with test$3 with mode$1 and (pre-charg$3 or precharg$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:42	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	7	(multi-chip$1 or multi adj chip$1) and (transit$6 or transfer$3) with (normal or operat$5) with test$3 with mode$1 and (pre-charg$3 or precharg$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 13:42	
2	BRS	13	test$3 with (multi-chip$1 or multi adj chip$1) and (stand-by or standby) with (voltage$1 or power$1 or electric or current$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:41	
3	BRS	2	"20040027150"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 14:08	
4	BRS	2	"20040027150"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:20	
5	BRS	2	"20040196709"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:21	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
6	BRS	2	"20040150089"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:22	
7	BRS	2	"20040100296"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:24	
8	BRS	2	"20030235929"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:24	
9	BRS	2	"20020017720"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:25	
10	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and clos$3 with memory with page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:30	
11	BRS	16	test$3 with (multi-chip$1 or multi adj chip$1) and memory with page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
12	BRS	3	test$3 with (multi-chip$1 or multi adj chip$1) and memory adj page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:31	
13	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and (pre-charg$3 or precharg$3) with memory with page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:34	
14	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and (pre-charg$3 or precharg$3) same memory with page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:34	
15	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and (pre-charg$3 or precharg$3) and memory with page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:34	
16	BRS	3	test$3 with (multi-chip$1 or multi adj chip$1) and memory adj page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:35	
17	BRS	3	test$3 with (multi-chip$1 or multi adj chip$1) and memory near page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:35	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
18	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and clos$3 near page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:35	
19	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and clos$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:36	
20	BRS	570	clos$3 with memory with page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:36	
21	BRS	0	(multi-chip$1 or multi adj chip$1) and clos43 with memory with page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:36	
22	BRS	24	(multi-chip$1 or multi adj chip$1) and clos$3 with memory with page$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:42	
23	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and memory with (page adj off or pageoff or page-off)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:39	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
24	BRS	0	test$3 with (multi-chip$1 or multi adj chip$1) and memory with (page$1 adj off or pageoff or page-off)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:39	
25	BRS	9	(multi-chip$1 or multi adj chip$1) and memory with (page$1 adj off or pageoff or page-off)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:40	
26	BRS	0	test$3 same (multi-chip$1 or multi adj chip$1) and memory with (page$1 adj off or pageoff or page-off)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:41	
27	BRS	0	test$3 same (multi-chip$1 or multi adj chip$1) and memory with (page$1 adj off or pageoff or page-off or clos$3 with page$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:42	
28	BRS	0	test$3 and (multi-chip$1 or multi adj chip$1) and memory with (page$1 adj off or pageoff or page-off or clos$3 with page$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:42	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
29	BRS	24	(multi-chip$1 or multi adj chip$1) and memory with (page$1 adj off or pageoff or page-off or clos$3 with page$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:42	
30	BRS	23	(multi-chip$1 or multi adj chip$1) and clos$3 with memory with page$1 and (pre-charg$3 or precharg$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:43	
31	BRS	23	(multi-chip$1 or multi adj chip$1) and clos$3 with memory with page$1 with (pre-charg$3 or precharg$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/08 15:43	